

Aanbesteding: PLD Research Cluster Basis
Aanbestedende Dienst: Stichting Nederlandse Wetenschappelijk Onderzoek Instituten (NWO-I)
Referentie: Differ_21_45

Toelichting:

Ref.nr. **Onderwerp:**
1 Award criteria / general

Vraag:

In Annex C – PLD – Award criteria, as part of the tender documents, lines 4 and 5, it is requested to show experimental data of three samples, focusing on sample-to-sample variance and thickness uniformity. The requested growth parameters are at least 100nm film thickness, grown at a deposition temperature of 700 degrees Celcius.

These conditions imply that films should show epitaxy and a high degree of crystallinity in for instance heterostructures, we presume these film characteristics and properties are an important part in the evaluation of the experimental data presented by the tenderer. Is this correct?

Antwoord:

Yes, the Contracting Authority agrees. Proof of epitaxial growth over a wafer, e.g. using the intensity of x-ray lines, shows sufficient control over the deposition process and thus sample uniformity and sample-to-sample repeatability.

To increase the pool of existing samples to be used as proof of award criteria 4 and 5 of Annex C, have been slightly reformulated as shown in the document "Changes to Award Criteria 4 and 5". In this document the underlined text has been changed.

Percelen: P1 PLD Research Cluster Basis
Beantwoord op: 18 dec. 2023
Label: Inhoud

Ref.nr. **Onderwerp:**
2 General

Vraag:

Will the offer, technical solutions and documentation we provide handled as confidential and not shared with other parties?

Antwoord:

Yes, all documentation send in with the offering will be handled

confidential. The Contracting Authority does want to stipulate that information on the awarding model (that includes the quality points awarded and the price per quality point) will be shared with all participants that submitted a tender.

Percelen: P1 PLD Research Cluster Basis
Beantwoord op: 18 dec. 2023
Label: Juridisch